

# **Notice of References Cited**

Application/Control No.

09/518,697

Applicant(s)/Patent Under  
Reexamination  
WAKELAM ET AL.

Examiner

Jones

Art Unit

2128

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US- 5,189,606	2/93	Burns et al.	705/10
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	C	US-			
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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	N					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Li et al.; A feature based parametric modeling system for CAD/CAPP/CAM integrated system; IEEE Int Conf Indust. Tech.; pp. 329-333; 12/1996.
	V	Krishnan et al.; Parametric model: a conceptual framework for geometric modelling databases; Sec. Int Conf Data and Knowledge Sys for Manufacturing and Engineering; pp. 161-171; 10/1989.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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